metrisis Film Metrology & More...

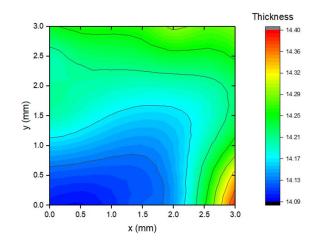
XY-M75 / XY-M100: Two-axes Linear Translation stage for FR-tools

XY-M linear stage is a dedicated accessory for FR-pOrtable and any FR-pRo tool. It allows the manual thickness & optical properties mapping of samples fast, easily and accurately.

The linear stage is offered in two travel ranges (75X55mm, 100X100mm) and is suitable for Reflectance, Transmittance measurements through the embedded optical window of up to 4-inch wafers.



Both XY-M stages (75X55mm and 100X100mm) are equipped with a knob and rulers to facilitate the movement at certain coordinates. The stage is mounted on the FR-tool and secures the probe at the center of the stage.



Thickness mapping (30mmX30mm) of SU-8 film spin coated on Si wafer with measurement step of 5mm, is illustrated. The thickness (scale bar in μ m) varies from 14.09 μ m to 14.40 μ m.

Features

- Manually controlled (knob on the top)
- Travel range: 100X100mm
- Sample: Dia. 100mm (max)
- Spring Clips
- o Reflectance & Transmittance
- Stage size: 285x205x330mm